

UTC UNISONIC TECHNOLOGIES CO., LTD

F50NM90-Q

Preliminary

Power MOSFET

50A, 900V N-CHANNEL SUPER-JUNCTION MOSFET

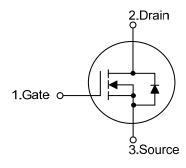
DESCRIPTION

The UTC F50NM90-Q is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at AC-DC converters for power applications.

FEATURES

- * $R_{DS(ON)} \le 0.13 \Omega$ @ V_{GS} =10V, I_D =25A
- * Fast switching capability
- * Avalanche energy tested
- * Improved dv/dt capability, high ruggedness

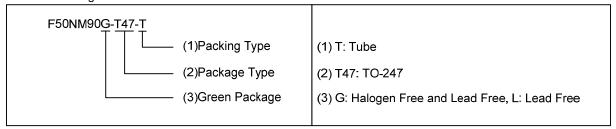
SYMBOL



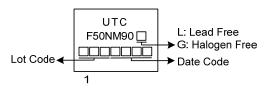
ORDERING INFORMATION

Ordering Number		Dardana	Pin Assignment			Da alsinan	
Lead Free	Halogen Free	Package	1	2	3	Packing	
F50NM90L-T47-T	F50NM90G-T47-T	TO-247	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source

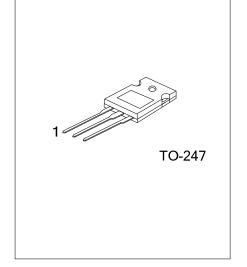


MARKING



www.unisonic.com.tw 1 of 5 QW-R205-977.a





■ ABSOLUTE MAXIMUM RATINGS (Tc=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	900	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Drain Current	Continuous	I_{D}	50	Α	
	Pulsed (Note 2)	I_{DM}	100	Α	
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	1300	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	10	V/ns	
Power Dissipation		P_D	350	W	
Junction Temperature		T_J	+150	°C	
Storage Temperature		T_{STG}	-55 ~ +150	°C	

- Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

 Absolute maximum ratings are stress ratings only and functional device operation is not implied.
 - 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
 - 3. L = 100mH, I_{AS} =5.1A, V_{DD} = 90V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
 - 4. $I_{SD} \leq 30 A$, di/dt $\leq 200 A/\mu s$, $V_{DD} \leq BV_{DSS}$, Starting T_J = 25°C

■ THERMAL DATA

PARAMETER	SYMBOL	RATING	UNIT	
Junction to Ambient	θЈΑ	40	°C/W	
Junction to Case	θјς	0.35	°C/W	

■ ELECTRICAL CHARACTERISTICS (T_J=25°C, unless otherwise specified)

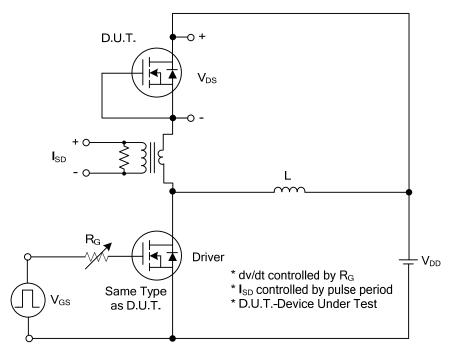
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250µA	900			V		
Drain-Source Leakage Current	I _{DSS}	V _{DS} =900V, V _{GS} =0V			10	μΑ		
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm30V$, $V_{DS}=0V$			±100	nA		
ON CHARACTERISTICS								
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$	2.5		4.5	V		
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =25A			0.13	Ω		
DYNAMIC CHARACTERISTICS								
Input Capacitance	Ciss			4888		pF		
Output Capacitance	Coss	V _{GS} =0V, V _{DS} =50V, f=1MHz		413		pF		
Reverse Transfer Capacitance	C _{RSS}			1.2		pF		
SWITCHING CHARACTERISTICS								
Total Gate Charge	Q_{G}	\/ -720\/ \/ -10\/ -50A		168		nC		
Gate-Source Charge	Q_GS	V _{DS} =720V, V _{GS} =10V, I _D =50A		40		nC		
Gate-Drain Charge	Q_{DD}	(Note 1, 2)		74		nC		
Turn-On Delay Time	t _{D(ON)}			24		ns		
Turn-On Rise Time	t _R	V _{DD} =100V, V _{GS} =10V, I _D =50A,		25		ns		
Turn-Off Delay Time	t _{D(OFF)}	R _G =3Ω (Note 1, 2)		108		ns		
Turn-Off Fall Time	t _F			28		ns		
SOURCE- DRAIN DIODE RATINGS AND C	HARACTERI	STICS						
Maximum Continuous Drain-Source Diode	l.				50	Α		
Forward Current	Is				30	^		
Maximum Pulsed Drain-Source Diode	I _{SM}				100	Α		
Forward Current	ISM				100	^		
Drain-Source Diode Forward Voltage	V _{SD}	I _S =50A, V _{GS} =0V			1.4	V		
Body Diode Reverse Recovery Time	t _{rr}	I _S =30A, V _{GS} =0V,		280		nS		
Body Diode Reverse Recovery Charge	Q_{rr}	dI _F /dt=100A/μs		2.85		μC		

Notes: 1. Pulse Test: Pulse width \leq 300µs, Duty cycle \leq 2%.

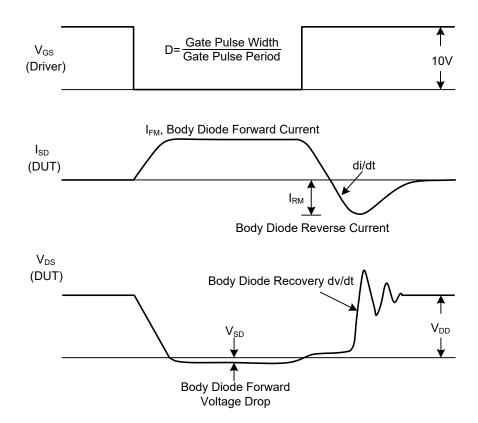
2. Essentially independent of operating temperature.



■ TEST CIRCUITS AND WAVEFORMS

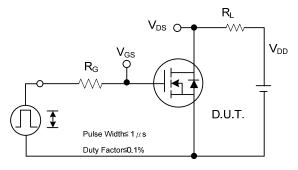


Peak Diode Recovery dv/dt Test Circuit

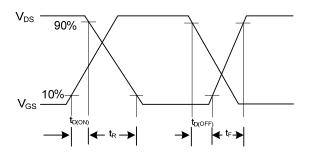


Peak Diode Recovery dv/dt Waveforms

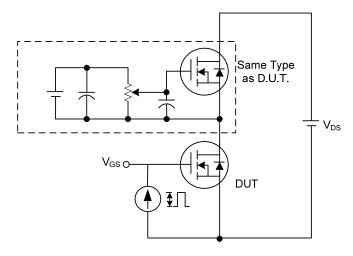
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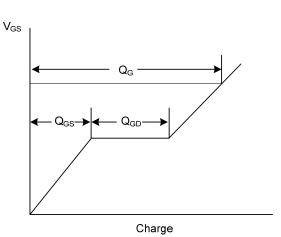
Switching Test Circuit



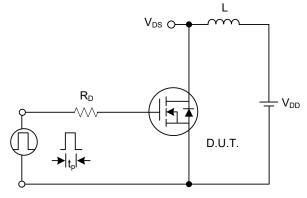
Switching Waveforms



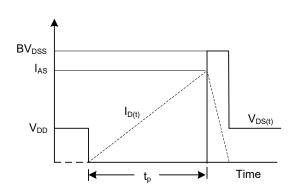
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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